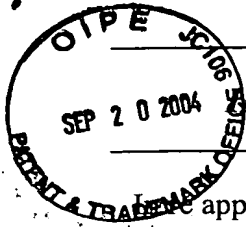


IFW



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Patent application of: Zhu et al.

Attorney Docket No.:
NOVLP090/NVLS-002888

Application No.: 10/733,858

Examiner: Not yet assigned

Filed: December 10, 2003

Group: 2812

Title: BIASED H₂ ETCH PROCESS IN
DEPOSITION-ETCH-DEPOSITION GAP
FILL

Confirmation No. 7860

CERTIFICATE OF MAILING

I hereby certify that this correspondence is being deposited with the U.S. Postal Service with sufficient postage as first-class mail on September 17, 2004 in an envelope addressed to the Commissioner for Patents, P.O. Box 1450 Alexandria, VA 22313-1450

Signed: _____

Mia Mitchell-Haynes

INFORMATION DISCLOSURE STATEMENT
37 CFR §§1.56 AND 1.97(b)

Mail Stop Amendment
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

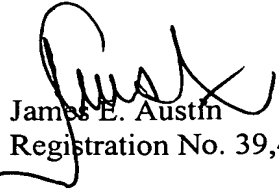
Dear Sir:

The references listed in the attached PTO Form 1449, may be material to examination of the above-identified patent application. Applicants submit these references in compliance with their duty of disclosure pursuant to 37 CFR §§1.56 and 1.97. The Examiner is requested to make these references of official record in this application.

This Information Disclosure Statement is not to be construed as a representation that a search has been made, that additional information material to the examination of this application does not exist, or that these references indeed constitute prior art.

This Information Disclosure Statement is: (i) filed within three (3) months of the filing date of the above-referenced application, (ii) believed to be filed before the mailing date of a first Office Action on the merits, or (iii) believed to be filed before the mailing of a first Office Action after the filing of a Request for Continued Examination under §1.114. Accordingly, it is believed that no fees are due in connection with the filing of this Information Disclosure Statement. However, if it is determined that any fees are due, the Commissioner is hereby authorized to charge such fees to Deposit Account 500388 (Order No. NOVLP090).

Respectfully submitted,
BEYER WEAVER & THOMAS, LLP



James E. Austin
Registration No. 39,489

P.O. Box 778
Berkeley, CA 94704-0778

Form 1449 (Modified)

Information Disclosure
Statement By Applicant

(Use Several Sheets if Necessary)

Atty Docket No.
NOVLP090/NVLS-2888

Applicant:

Zhu et al.

Filing Date

December 10, 2003

Application No.:

10/733,858

Group

2812

U.S. Patent Documents

Examiner Initial	No.	Patent No.	Date	Patentee	Class	Sub-class	Filing Date
	A1	5,705,419	01/1998	Perry et al.			
	A2	5,342,801	08/1994	Perry et al.			
	A3	5,385,857	01/1995	Solo de Zaldivar			
	A4	4,361,461	11/1982	Chang			
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	A6	5,270,264	12/1993	Andideh et al.			
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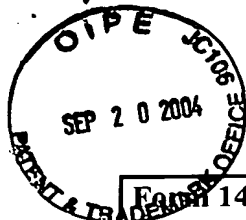
Foreign Patent or Published Foreign Patent Application

Examiner Initial	No.	Document No.	Publication Date	Country or Patent Office	Class	Sub-class	Translation	
							Yes	No

Other Documents

Examiner Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication
	C1	Papasouliotis et al., "Method of Chemical Modification of Structure Topography", U.S. Patent Application No. 10/004,386, filed December 3, 2001.
Examiner		Date Considered

Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



Form 1449 (Modified) Information Disclosure Statement By Applicant (Use Several Sheets if Necessary)	Atty Docket No. NOVLP090/NVLS-2888 Applicant: Zhu et al. Filing Date December 10, 2003 Application No.: 10/733,858 Group 2812
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Examiner Initial	No.	Patent No.	Date	Patentee	Class	Sub-class	Filing Date
	A9	5,282,925	2/1994	Jeng et al.			
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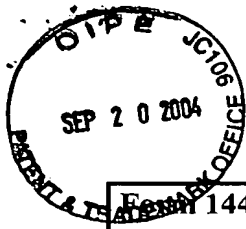
Foreign Patent or Published Foreign Patent Application

Examiner Initial	No.	Document No.	Publication Date	Country or Patent Office	Class	Sub-class	Translation	
							Yes	No

Other Documents

Examiner Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication
		Date Considered

Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



Form 1449 (Modified)	Atty Docket No. NOVLP090/NVLS-2888	Application No.: 10/733,858
Information Disclosure Statement By Applicant	Applicant: Zhu et al.	
(Use Several Sheets if Necessary)	Filing Date December 10, 2003	Group 2812

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	A35	6,395,150	5/2002	Van Cleemput et al.			

Foreign Patent or Published Foreign Patent Application

Examiner Initial	No.	Document No.	Publication Date	Country or Patent Office	Class	Sub-class	Translation	
							Yes	No

Other Documents

Examiner Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication
		Date Considered

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